

Resource Summary Report

Generated by [RRID](#) on Aug 5, 2026

JEOL: JIB-4700F Focused Ion Beam

RRID:SCR_020188

Type: Tool

Proper Citation

JEOL: JIB-4700F Focused Ion Beam (RRID:SCR_020188)

Resource Information

URL: <https://www.jeolusa.com/PRODUCTS/Focused-Ion-Beam/JIB-4700F>

Proper Citation: JEOL: JIB-4700F Focused Ion Beam (RRID:SCR_020188)

Description: Focused ion beam that can be used in morphological observations, elemental and crystallographic analyses of variety of specimens.

Resource Type: instrument resource

Keywords: Jeol, JEOL, Focused Ion Beam, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: JEOL: JIB-4700F Focused Ion Beam

Resource ID: SCR_020188

Alternate IDs: Model_Number_JIB-4700F

Record Creation Time: 20220129T080349+0000

Record Last Update: 20260801T190653+0000

Ratings and Alerts

No rating or validation information has been found for JEOL: JIB-4700F Focused Ion Beam.

No alerts have been found for JEOL: JIB-4700F Focused Ion Beam.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.